

# 1. General description

The TJA1083 FlexRay node transceiver is compliant with the FlexRay Electrical Physical Layer specification V3.0.1 (see <u>Ref. 1</u>). In order to meet JASPAR the equirements, it implements the 'Increased voltage amplitude transmitter' functional class. It is primarily intended for communication systems operating at between 2.5 Mbit/s and 10 Mbit/s, and provides an advanced interface between the protocol controller and the physical bus in a FlexRay network. The TJA1083 offers an optimized solution for Electronic Control Unit (ECU) applications that do not need enhanced power management and are typically switched by the ignition or activated by a dedicated wake-up line.

The TJA1083 provides a differential transmit capability to the network and a differential receive capability to the FlexRay controller. It offers excellent ElectroMagnetic Compatibility (EMC) performance as well as high ElectroStatic Discharge (ESD) protection.

The TJA1083 actively monitors system performance using dedicated error and status information (readable by any microcontroller), as well as internal voltage and temperature monitoring.

# 2. Features and benefits

## 2.1 Optimized for time triggered communication systems

- Compliant with Electrical Physical Layer specification V3.0.1
- Meets JASPAR requirements as described in the 'Bus driver increased voltage amplitude transmitter' functional class
- Automotive product qualification in accordance with AEC-Q100
- Data transfer rates from 2.5 Mbit/s to 10 Mbit/s
- Supports 60 ns minimum bit time at 400 mV differential input voltage
- Very low ElectroMagnetic Emission (EME) to support unshielded cable
- Differential receiver with high common-mode range for excellent ElectroMagnetic Immunity (EMI)
- Auto I/O level adaptation to host controller supply voltage V<sub>IO</sub>
- Can be used in 14 V, 24 V and 48 V powered systems
- Instant transmitter shut-down interface (BGE pin)

## 2.2 Low-power management

- Very low current consumption in Standby mode
- Remote wake-up via a wake-up pattern or dedicated FlexRay data frames on the bus lines



## 2.3 Diagnosis and robustness

- Enhanced supply voltage monitoring for V<sub>CC</sub> and V<sub>IO</sub>
- Two error diagnosis modes:
  - Status register readout via the Serial Peripheral Interface (SPI)
  - Simple error indication via pin ERRN
- Overtemperature detection
- Short-circuit detection on bus lines
- Power-on flag
- Clamping diagnosis for pins TXEN and BGE
- Bus pins protected against ±6 kV ESD pulses according to IEC61000-4-2 and ±8 kV according to HBM
- Bus pins protected against transients in automotive environment (according to ISO 7637 class C)
- Bus pins short-circuit proof to battery voltage (14 V, 24 V and 48 V) and ground
- Maximum differential voltage between pins BP or BM and any other pin of  $\pm 60 \text{ V}$
- Bus lines remain passive when the transceiver is not powered
- No reverse currents from the digital input pins to V<sub>IO</sub> or V<sub>CC</sub> when the transceiver is not powered

# 2.4 Functional classes according to FlexRay Electrical Physical Layer specification V3.0.1

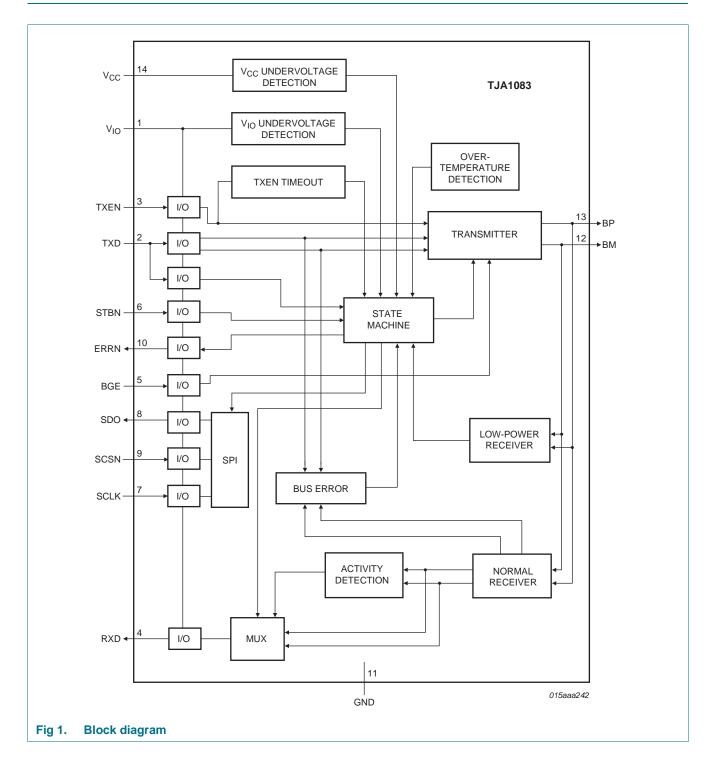
- Bus driver increased voltage amplitude transmitter
- Bus driver bus guardian control interface
- Bus driver logic level adaptation
- Bus driver remote wake-up

# 3. Ordering information

#### Table 1.Ordering information

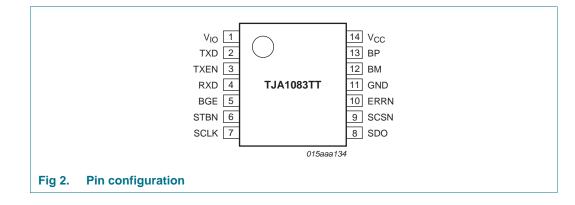
Type number	Package						
	Name	Description	Version				
TJA1083TT	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1				

# 4. Block diagram



# 5. Pinning information

# 5.1 Pinning



## 5.2 Pin description

#### Table 2. Pin description

		1	
Symbol	Pin	Туре	Description
V <sub>IO</sub>	1	Р	supply voltage for $V_{IO}$ voltage level adaptation
TXD	2	I	transmit data input; internal pull-down
TXEN	3	I	transmitter enable input; when HIGH transmitter disabled; internal pull-up
RXD	4	0	receive data output
BGE	5	I	bus guardian enable input; when LOW transmitter disabled; internal pull-down
STBN	6	I	mode control input; transceiver in Normal mode when HIGH; internal pull-down
SCLK	7	I	SPI clock signal; internal pull-up
SDO	8	0	SPI data output
SCSN	9	I	SPI chip select input; internal pull-up/pull-down
ERRN	10	0	error diagnosis output and wake-up indication
GND	11	Р	ground
BM	12	I/O	bus line minus
BP	13	I/O	bus line plus
V <sub>CC</sub>	14	Р	supply voltage (+5 V)

# 6. Functional description

## 6.1 Power modes

The TJA1083 features three power modes: Normal, Standby and Power-off. Normal and Standby modes can be selected via the STBN input (HIGH for Normal mode) once the transceiver has been powered up. See <u>Table 3</u> for a detailed description of pin signaling in the three power modes.

	•														
Mode	STBN	UV at V <sub>IO</sub>	UV at V <sub>CC</sub>	ERRN LOW	i High	RXD LOW	HIGH	SDO	Biasing BP, BM	UV-det	Trans- mitter	Low- power receiver			
Normal	HIGH	no	no	error flag set	error flag reset	bus DATA _0	bus DATA_1 or idle	high- impedance (in simple	V <sub>CC</sub> / 2	enabled	enabled	enabled <sup>[1]</sup>			
Standby	LOW	no	no	wake flag set	wake flag reset	wake flag set	wake flag reset	error indication mode) or enabled	GND					disabled	enabled <sup>[2]</sup>
	LOW	no	yes <mark>[3]</mark>	wake flag set <mark>[4]</mark>	wake flag reset <sup>[4]</sup>	wake flag set <sup>[4]</sup>	wake flag reset <sup>[4]</sup>	(in SPI mode)				disabled			
	HIGH	no	yes <mark>[3]</mark>	error flag set	error flag reset	wake flag set <sup>[4]</sup>	wake flag reset <sup>[4]</sup>								
	Х	yes <mark>[5]</mark>	no	LOW		LOW		high-			enabled <sup>[2]</sup>				
	Х	yes <mark>[5]</mark>	yes <mark>[3]</mark>	LOW		LOW		impedance				disabled			
Power-off	Х	Χ <u>[5]</u>	yes	high- imped	ance	HIGH			GND <sup>[6]</sup>	disabled		disabled			

#### Table 3. Pin signaling in the different power modes

[1] The wake flag is set if a valid wake-up event is detected while switching to Standby mode.

[2] The wake flag is set if a valid wake-up event is detected.

[3]  $V_{uvd(VCC)} > V_{CC} > V_{th(det)POR}$ .

[4] Pins ERRN and RXD reflect the state of the wake flag prior to the V<sub>CC</sub> undervoltage event.

[5] The internal signals at pins STBN, BGE and TXD are set LOW; the internal signals at pins TXEN, SCLK and SCSN are set HIGH.

[6] Except when  $V_{CC} = 0$ ; in this case BP and BM are floating.

### 6.1.1 Normal mode

In Normal mode, the transceiver transmits and receives data via the bus lines BP and BM. The transmitter and the normal receiver are enabled, along with the undervoltage detection function. The timing diagram for Normal mode is illustrated in Figure 3.

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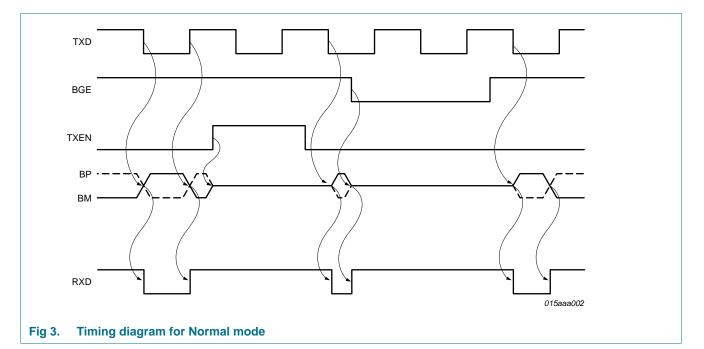


Table 4 describes the behavior of the transmitter in Normal mode, when the temperature flag (TEMP HIGH) is not set and with no time-out on pin TXEN. Transmitter behavior is illustrated in Figure 13.

BGE	TXEN	TXD	Bus state	Transmitter
L	Х	Х	idle	transmitter is disabled
Х	Н	Х	idle	transmitter is disabled
Η	L	Η	DATA_1	transmitter is enabled; the bus lines are actively driven; BP is driven HIGH and BM is driven LOW
Η	L	L	DATA_0	transmitter is enabled; the bus lines are actively driven; BP is driven LOW and BM is driven HIGH

#### Table 4. **Transmitter operation in Normal mode**

The transmitter is activated during the first LOW level on pin TXD while pin BGE is HIGH and pin TXEN is LOW.

In Normal mode, the normal receiver output is connected directly to pin RXD (see Table 5). Receiver behavior is illustrated in Figure 14.

Table 5.	Behavior of normal receiver in Normal mode	
Bus state	RXD	

Bus state	RXD
DATA_0	L
DATA_1	Н
idle	Н

When  $V_{IO}$  and  $V_{CC}$  are within their operating ranges, pin ERRN indicates the status of the error flag. See Section 6.8 for a detailed description of error signaling in Normal mode.

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#### 6.1.1.1 Bus activity and idle detection

In Normal mode, bus activity and bus idle are detected as follows:

- Bus activity is detected when the absolute differential voltage on the bus lines is higher than |V<sub>i(dif)det(act)</sub>| for t<sub>det(act)(bus)</sub>:
  - If the differential voltage on the bus lines is lower than V<sub>IL(dif)</sub> after bus activity has been detected, pin RXD switches LOW.
  - If the differential voltage on the bus lines is higher than V<sub>IH(dif)</sub> after bus activity has been detected, pin RXD remains HIGH.
- Bus idle is detected when the absolute differential voltage on the bus lines is lower than |V<sub>i(dif)det(act)</sub>| for t<sub>det(idle)(bus)</sub>. This results in pin RXD being switched HIGH or staying HIGH.

#### 6.1.2 Standby mode

Standby mode is a low-power mode featuring very low current consumption. In Standby mode, the transceiver is unable to transmit or receive data since both the transmitter and the normal receiver are switched off. The low-power receiver is activated to monitor the bus for wake-up activity, provided an undervoltage has not been detected on pin V<sub>CC</sub>.

The low-power receiver is deactivated if an undervoltage is detected on pin  $V_{CC}$  - with the result that the wake flag is not set if a wake-up pattern or dedicated data frame is received.

Pins ERRN and RXD indicate the status of the wake flag when  $V_{IO}$  and  $V_{CC}$  are within their operating ranges. See <u>Table 3</u> for a description of pins ERRN and RXD when an undervoltage is detected on pin  $V_{IO}$  or pin  $V_{CC}$ .

The status register cannot be read via the SPI interface if an undervoltage is detected on pin  $V_{\text{IO}}.$ 

The BGE input has no effect in Standby mode.

#### 6.1.3 Power-off mode

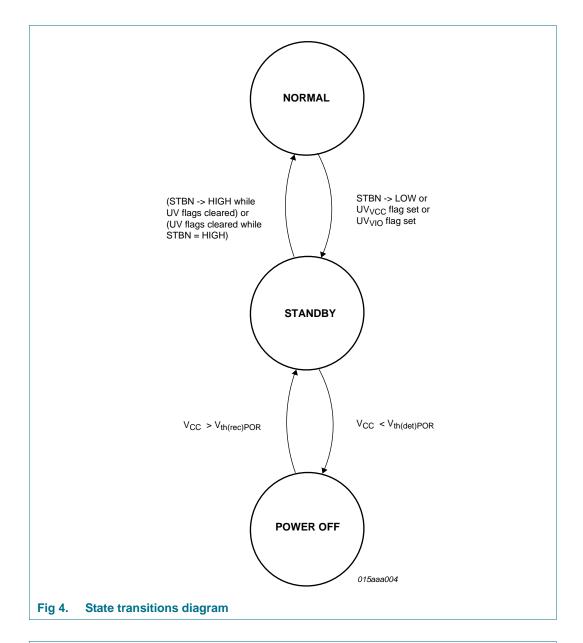
The transmitter and the two receivers (normal and low-power) are deactivated in Power-off mode. As a result, the wake flag is not set if a wake-up pattern or dedicated data frame is received. If the voltage at  $V_{CC}$  rises above  $V_{th(rec)POR}$ , the transceiver switches to Standby mode and the digital section is reset. If  $V_{CC}$  subsequently drops below  $V_{th(det)POR}$ , the transceiver reverts to Power-off mode (see Section 6.2).

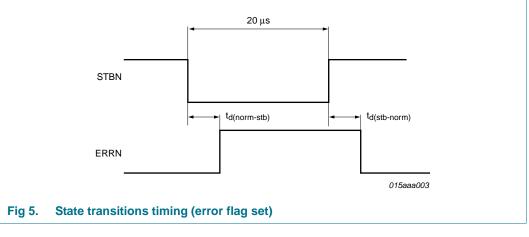
The status register cannot be read via the SPI interface in Power-off mode.

#### 6.1.4 State transitions

<u>Figure 4</u> shows the TJA1083 state transition diagram. The timing diagram for the ERRN indication signal during transitions between Normal and Standby modes, when the error flag is set and the wake flag is not set, is illustrated in <u>Figure 5</u> and described in <u>Table 6</u>.

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Transition	UVV <sub>IO</sub> flag <mark>[1]</mark>	UVV <sub>CC</sub> flag <mark><sup>[1]</sup></mark>	wake flag <sup>[1]</sup>	PWON flag <sup>[1]</sup>	STBN	VCC level
Normal to Standby	cleared	cleared	cleared	cleared	$\rightarrow$ L	$V_{CC} > V_{uvd(VCC)}$
	$\rightarrow$ set	cleared	cleared	cleared	Н	$V_{CC} > V_{uvd(VCC)}$
	cleared	$\rightarrow$ set	cleared	cleared	Н	$V_{uvd(VCC)} > V_{CC} > V_{th(det)POR}$
Standby to Normal	cleared	cleared	$1 \rightarrow cleared$	$2 \rightarrow cleared$	$\rightarrow$ H	$V_{CC} > V_{uvd(VCC)}$
	$\rightarrow$ cleared	cleared	$1 \rightarrow cleared$	$2 \rightarrow cleared$	Н	$V_{CC} > V_{uvd(VCC)}$
	cleared	$\rightarrow$ cleared	$1 \rightarrow cleared$	$2 \rightarrow cleared$	Н	$V_{uvd(VCC)} > V_{CC} > V_{th(det)POR}$
Standby to Power-off	Х	set	Х	Х	Х	$\rightarrow$ V <sub>CC</sub> < V <sub>th(det)</sub> POR
Power-off to Standby	Х	set	Х	$1 \rightarrow set$	Х	$\rightarrow V_{CC} > V_{th(rec)POR}$

#### Table 6.State transitions

ightarrow indicates the action that initiates a transaction; 1 ightarrow and 2 ightarrow are the consequences of a transaction

[1] See <u>Table 7</u> for set and reset conditions of all flags.

## 6.2 Power-up and power-down behavior

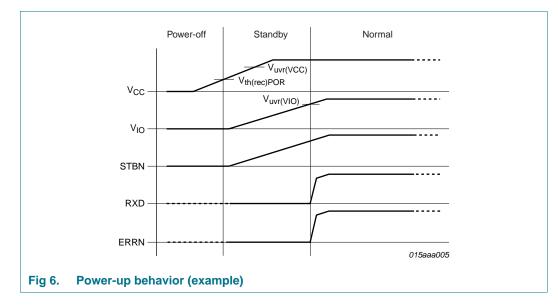
#### 6.2.1 Power-up

The TJA1083 has two supply pins:  $V_{CC}$  (+5 V) and  $V_{IO}$  (for the voltage level adaptation). The ramp up of the different power supplies can vary, depending on the state or value of a number of signals and parameters. The power-up behavior of the TJA1083 is not affected by the sequence in which power is supplied to these pins or by the voltage ramp up.

As an example, Figure 6 shows one possible power supply ramp-up scenario. The digital section of the TJA1083 is supplied by V<sub>CC</sub>. The voltage on pin V<sub>CC</sub> ramps up before the voltage on pin V<sub>IO</sub>. As long as the voltage on V<sub>CC</sub> remains below the power-on reset recovery threshold, V<sub>th(rec)POR</sub>, the internal state machine is inactive and the transceiver is totally passive, remaining in Power-off mode. As soon as the voltage rises above the V<sub>th(rec)POR</sub> threshold, the internal state machine starts running, setting the PWON flag and switching the TJA1083 to Standby mode. This initializes the V<sub>CC</sub> and V<sub>IO</sub> under-voltage flags to the set state (since both V<sub>CC</sub> and V<sub>IO</sub> are actually in undervoltage state just after power-on).

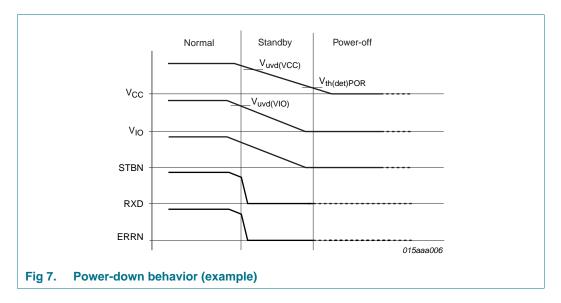
Once both V<sub>IO</sub> and V<sub>CC</sub> have reached their operating ranges, the under-voltage flags are reset. The operating mode is then determined by the level on STBN (the TJA1083 switches to Normal mode if STBN is HIGH and remains in Standby mode if STBN is LOW), provided V<sub>IO</sub> and V<sub>CC</sub> are above their respective undervoltage recovery levels (V<sub>uvr(VIO</sub>) and V<sub>uvr(VCC</sub>)).

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### 6.2.2 Power-down

The behavior of the TJA1083 during power-down is illustrated in Figure 7.

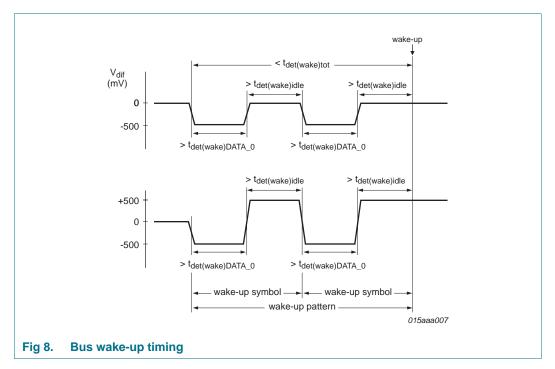


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## 6.3 Remote wake-up

#### 6.3.1 Bus wake-up via wake-up pattern

A valid remote wake-up event occurs when a wake-up pattern is received. A wake-up pattern consists of at least two consecutive wake-up symbols. A wake-up symbol comprises a DATA\_0 phase lasting longer than  $t_{det(wake)DATA_0}$  followed by an idle phase lasting longer than  $t_{det(wake)idle}$ , provided both wake-up symbols occur within a time span of  $t_{det(wake)tot}$  (see Figure 8). The transceiver also wakes up if DATA\_1 phases are substituted for the idle phases.



See Ref. 1 for more details of the wake-up mechanism.

#### 6.3.2 Bus wake-up via dedicated FlexRay data frame

The TJA1083 wake flag is set when a dedicated data frame emulating a valid wake-up pattern, as shown in Figure 9, is received.

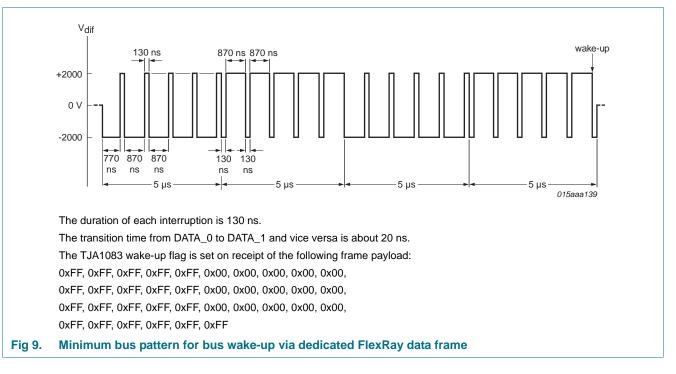
The DATA\_0 and DATA\_1 phases of the emulated wake-up symbol are interrupted by the Byte Start Sequence (BSS) preceding each byte in the data frame. With a data rate of 10 Mbit/s, the interruption has a maximum duration of 130 ns and does not prevent the transceiver from recognizing the wake-up pattern in the payload.

For longer interruptions at lower data rates (5 Mbit/s and 2.5 Mbit/s), the wake-up pattern should be used (see <u>Section 6.3.1</u>).

The wake flag is not set if an invalid wake-up pattern is received. See <u>Ref. 1</u> for more details on invalid wake-up patterns.

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### 6.4 Bus error detection

The TJA1083 detects the following bus errors during transmission:

- Short-circuit BP to BM at the ECU connector or on the bus
- Short-circuit BP to GND at the ECU connector or on the bus
- · Short-circuit BM to GND at the ECU connector or on the bus
- Short-circuit BP to V<sub>CC</sub> at the ECU connector or on the bus
- Short-circuit BM to V<sub>CC</sub> at the ECU connector or on the bus

The bus error flag is not set when a wake-up pattern or a FlexRay Collision Avoidance Symbol (CAS) is being transmitted or received.

## 6.5 Fail silent behavior

Three mechanisms guarantee the 'fail silent' behavior of the TJA1083:

- The TXEN clamped flag is set if pin TXEN goes LOW for longer than t<sub>detCL(TXEN)</sub> in Normal mode; the transmitter is disabled.
- The BGE clamped flag is set if pin BGE goes HIGH for longer than t<sub>detCL(BGE)</sub> in Normal mode; no action is taken.
- If a loss-of-ground occurs at the transceiver, resulting in the TJA1083 switching to Power-off mode, no current flows out of the digital input pins (TXD, TXEN, BGE, STBN, SCLK, SCSN); see <u>Table 3</u> for details of the behavior of the bus pins.

## 6.6 TJA1083 flags

The TJA1083 has 11 status/error flags. These are described in Table 7.

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		ags and settleset conditio			
Flag name	Flag type	Flag description	Set condition	Reset condition <sup>[1]</sup>	Consequence of flag set
bus wake	status flag	indicates if a wake-up event has occurred	wake-up event on bus in Standby mode <sup>[2]</sup>	transition to Normal mode	$\begin{array}{l} RXD \rightarrow LOW;\\ ERRN \rightarrow LOW \ \underline{[3]} \end{array}$
Normal mode	status flag	indicates if the transceiver is in Normal mode	entering Normal mode	leaving Normal mode	-
transmitter enabled	status flag	indicates the transmitter status	transmitter enabled <sup>[4]</sup>	transmitter disabled	-
BGE clamped	status flag	indicates if pin BGE is clamped	BGE HIGH for longer than t <sub>detCL(BGE)</sub> <sup>[5]</sup>	BGE LOW <sup>[5]</sup>	•
PWON	status flag	indicates when the digital section is initialized	$V_{CC} > V_{th(rec)POR}$	transition to Normal mode	-
bus error	error flag	indicates if a bus error has been detected	bus error detected <sup>[5]</sup>	no bus error detected or positive edge on TXEN <sup>[5]</sup>	ERRN $\rightarrow$ LOW [6]
TEMP HIGH	error flag	indicates if the max. junction temperature has been reached	$T_{vj} > T_{j(dis)(high)}^{[5]}$	$\begin{array}{l} \text{TXEN} = \text{HIGH while} \\ \text{T}_{\text{vj}} < \text{T}_{j(\text{dis})(\text{high})}^{[5]} \end{array}$	ERRN $\rightarrow$ LOW <sup>[6]</sup> ; transmitter disabled
TXEN clamped	error flag	indicates if pin TXEN is clamped	TXEN LOW for longer than t <sub>detCL(TXEN)</sub> [5]	TXEN = HIGH <sup>[5]</sup>	ERRN $\rightarrow$ LOW [6]; transmitter disabled
UVV <sub>CC</sub>	error flag	indicates if there is an undervoltage at pin $V_{\mbox{CC}}$	$V_{CC} < V_{uvd(VCC)}$ for longer than $t_{det(uv)(VCC)}$	$V_{CC} > V_{uvr(VCC)}$ for longer than $t_{rec(uv)(VCC)}$	ERRN $\rightarrow$ LOW <sup>[6]</sup> ; entering Standby mode
UVV <sub>IO</sub>	error flag	indicates if there is an undervoltage at pin $V_{\text{IO}}$	$V_{IO} < V_{uvd(VIO)}$ for longer than $t_{det(uv)(VIO)}$	$\label{eq:VIO} \begin{split} V_{IO} &> V_{uvr(VIO)} \text{ for longer} \\ than \ t_{rec(uv)(VIO)} \end{split}$	ERRN $\rightarrow$ LOW <sup>[6]</sup> ; entering Standby mode
SPI error	error flag	indicates if an SPI error has occurred	SPI error detected <sup>[8]</sup>	falling edge on SCSN	ERRN $\rightarrow$ LOW [7]; SDO goes to a high impedance state

#### Table 7. TJA1083 flags and set/reset conditions

[1] All flags, except for the PWON flag, are reset after a power-on reset.

[2] If an undervoltage has not been detected on pin  $V_{CC}$ .

[3] If STBN = LOW.

[4] If BGE = HIGH, the Normal mode flag is set, the TEMP HIGH flag is not set and the TXEN clamped flag is not set.

- [5] Flag can only be set or reset in Normal mode or on leaving Normal mode.
- [6] If STBN = HIGH.
- [7] If STBN = HIGH in SPI mode
- [8] The SPI error flag is set when:

a) more than 16 falling edges occur on pin SCLK while pin SCSN = LOW

b) less than 16 falling edges occur on pin SCLK while pin SCSN = LOW.

## 6.7 TJA1083 status register

The TJA1083 contains a 16-bit status register, of which bits S0 to S4 reflect the state of the status flags, bits S5 to S10 reflect the state of the error flags and bit S15 is a parity bit. All flags can be individually read out on pin SDO via a 16-bit SPI interface when the transceiver is configured in SPI mode. The status register bits are described in <u>Table 8</u>.

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Table o.	IJA 1005 Status re	giatei	
Status bit	Flag name	Set condition	Reset condition
S0	bus wake	bus wake flag set	bus wake flag cleared
S1	Normal mode	Normal mode flag set	Normal mode flag cleared
S2	transmitter enabled	transmitter enabled flag set	transmitter enabled flag cleared
S3	BGE clamped	BGE clamped flag set	BGE clamped flag cleared
S4	PWON	PWON flag set	PWON flag cleared and successful readout <sup>[1]</sup>
S5	bus error	bus error flag set	bus error flag cleared and successful readout <sup>[1]</sup>
S6	TEMP HIGH	TEMP HIGH flag set	TEMP HIGH flag cleared and successful readout <sup>[1]</sup>
S7	TXEN clamped	TXEN clamped flag set	TXEN clamped flag cleared and successful readout <sup>[1]</sup>
S8	UVV <sub>CC</sub>	$\mathrm{UVV}_{\mathrm{CC}}$ flag set	UVV <sub>CC</sub> flag cleared and successful readout <sup>[1]</sup>
S9	UVV <sub>IO</sub>	UVV <sub>IO</sub> flag set	UVV <sub>IO</sub> flag cleared and successful readout <sup>[1]</sup>
S10	SPI error	SPI error flag set	SPI error flag cleared and successful readout <sup>[1]</sup>
S11	reserved	always LOW	
S12	reserved	always HIGH	
S13	reserved	always LOW	
S14	reserved	always HIGH	
S15	parity bit	odd parity of status bits	even parity of status bits

#### Table 8. TJA1083 status register

[1] Also cleared during Power-off.

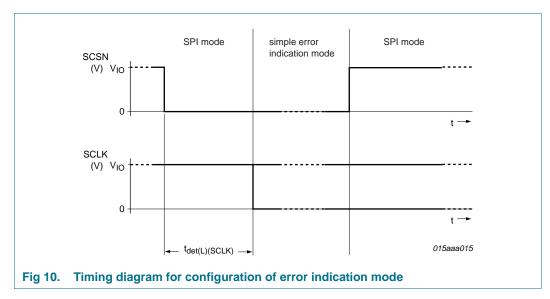
## 6.8 Error signaling

The TJA1083 provides two modes for error indication:

- Simple error indication mode
- SPI mode (default mode)

SPI mode is active on power-up.

To switch to simple error indication mode, SCSN must be held LOW (connected to GND) and SCLK held HIGH (connected to V<sub>IO</sub>) for longer than  $t_{det(L)(SCLK)}$  (provided a V<sub>IO</sub> undervoltage has not occurred). When the TJA1083 is in simple error indication mode, a rising edge on SCSN initiates a transition to SPI mode (again provided a V<sub>IO</sub> undervoltage has not occurred); see Figure 10.



If a  $V_{IO}$  undervoltage condition is detected, it is not possible to switch between SPI mode and simple error indication mode.

### 6.8.1 SPI mode

The error flag information in the status register is latched in SPI mode. This means that the status bit is reset once the status register has been completely read (provided the corresponding error flag has been reset). If an error condition is detected in Normal mode, pin ERRN goes LOW (provided one of the error bits, S5 to S10, is set). Pin ERRN goes HIGH again once all the error bits have been reset.

## 6.8.2 Simple error indication mode

If an error condition is detected in Normal mode, pin ERRN goes LOW once the relevant error flag has been set. Pin ERRN stays stable for at least  $t_{ERRNL(min)}$  and goes HIGH again when all error conditions have been cleared and all flags have been reset. Error flags are not latched. It is not possible to read-out the status bits in this mode.

## 6.9 SPI interface

The TJA1083 includes a 16-bit SPI interface to enable a host to read the status register when the transceiver is in SPI mode (see <u>Section 6.8</u>).

While pin SCSN is HIGH, the SDO output is in a high-impedance state. To begin a status register readout, the host must force pin SCSN LOW. This action causes the SDO pin to output a LOW level by default. The data on pin SDO is then shifted out on the rising edge of the clock signal on pin SCLK.

The status bits shifted out on pin SDO are active HIGH. The status bits are refreshed and pin SDO returned to a high-impedance state once the status register has been read successfully (after exactly 16 clock cycles) and SCSN has been forced HIGH again. Clock signals on SCLK are ignored while SCSN is HIGH. The timing diagram for the SPI readout is illustrated in Figure 11.

The SLCK period ranges from 500 ns to 100  $\mu$ s (10 kbit/s to 2 Mbit/s).

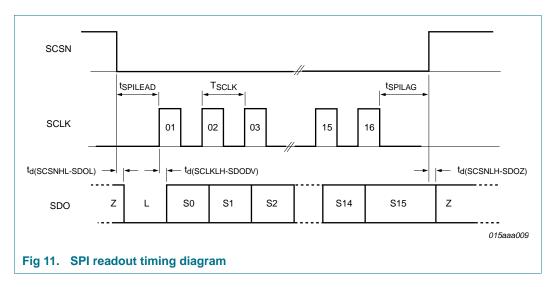
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If SCSN remains LOW for longer than 16 clock cycles, it is recognized as an SPI error. When this happens, the SPI error flag is set and pin SDO goes to a high-impedance state until the next falling edge on pin SCSN.

An SPI error is also assumed if fewer than 16 clock cycles are received while SCSN is LOW. If this happens, the SPI error flag is set.

All status bits are refreshed once the status register has been successfully read.

When the transceiver is in simple error indication mode the SDO output is in a high-impedance state and pin SCSN is in pull-down mode. In SPI mode pin SCSN is in pull-up mode.



SPI readout is not possible when the transceiver has detected an undervoltage on VIO.

# 7. Limiting values

#### Table 9. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). All voltages are referenced to GND.

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage	no time limit	-0.3	+5.5	V
V <sub>IO</sub>	supply voltage on pin V <sub>IO</sub>	no time limit	-0.3	+5.5	V
V <sub>ERRN</sub>	voltage on pin ERRN	no time limit	-0.3	V <sub>IO</sub> + 0.3	V
V <sub>RXD</sub>	voltage on pin RXD	no time limit	-0.3	V <sub>IO</sub> + 0.3	V
V <sub>SDO</sub>	voltage on pin SDO	no time limit	-0.3	V <sub>IO</sub> + 0.3	V
V <sub>TXEN</sub>	voltage on pin TXEN	no time limit	-0.3	+5.5	V
V <sub>TXD</sub>	voltage on pin TXD	no time limit	-0.3	+5.5	V
V <sub>STBN</sub>	voltage on pin STBN	no time limit	-0.3	+5.5	V
V <sub>SCSN</sub>	voltage on pin SCSN	no time limit	-0.3	+5.5	V
V <sub>SCLK</sub>	voltage on pin SCLK	no time limit	-0.3	+5.5	V
V <sub>BGE</sub>	voltage on pin BGE	no time limit	-0.3	+5.5	V
V <sub>BP</sub>	voltage on pin BP	no time limit (with respect to pins BM and GND)	-60	+60	V

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#### Table 9. Limiting values ...continued

In accordance with the Absolute Maximum Rating System (IEC 60134). All voltages are referenced to GND.

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>BM</sub>	voltage on pin BM	no time limit (with respect to pins BP and GND)	-60	+60	V
I <sub>I(ERRN)</sub>	input current on pin ERRN	no time limit; $V_{IO} = 0 V$	-10	10	mA
I <sub>I(RXD)</sub>	input current on pin RXD	no time limit; $V_{IO} = 0 V$	-10	10	mA
I <sub>I(SDO)</sub>	input current on pin SDO	no time limit; V <sub>IO</sub> = 0 V	-10	10	mA
V <sub>trt</sub>	transient voltage	on pins BM and BP	<u>[1]</u> –100	-	V
			[2] _	75	V
			<u>[3]</u> –150	-	V
			[4]	100	V
T <sub>stg</sub>	storage temperature		-55	+150	°C
Τ <sub>vj</sub>	virtual junction temperature		<u>[5]</u> –40	+150	°C
T <sub>amb</sub>	ambient temperature		-40	+125	°C
V <sub>ESD</sub>	electrostatic discharge voltage	IEC61000-4-2 on pins BP and BM to ground	<u>6</u> –6.0	+6.0	kV
		HBM on pins BP and BM to ground	<u>[7]</u> –8.0	+8.0	kV
		HBM on any other pin	<u>[7]</u> –4.0	+4.0	kV
		MM on all pins	<u>8</u> –200	+200	V
		CDM on all pins	<u>9</u> –1000	+1000	V

[1] According to ISO7637, test pulse 1, class C; verified by an external test house.

[2] According to ISO7637, test pulse 2a, class C; verified by an external test house.

[3] According to ISO7637, test pulse 3a, class C; verified by an external test house.

[4] According to ISO7637, test pulse 3b, class C; verified by an external test house.

[5] In accordance with IEC 60747-1. An alternative definition of  $T_{vj}$  is:  $T_{vj} = T_{amb} + P \times R_{th(j-a)}$ , where  $R_{th(j-a)}$  is a fixed value used in the calculation of  $T_{vj}$ . The rating for  $T_{vj}$  limits the allowable combinations of power dissipation (P) and ambient temperature ( $T_{amb}$ ).

[6] IEC61000-4-2: C = 150 pF; R = 330 Ω; verified by an external test house; the test results were equal to or better than ±6 kV (unaided).

[7] HBM: C = 100 pF; R = 1.5 k $\Omega$ .

[8] MM: C = 200 pF; L = 0.75  $\mu$ H; R = 10  $\Omega$ .

[9] CDM: R = 1 Ω.

# 8. Thermal characteristics

#### Table 10.Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	130	K/W

# 9. Static characteristics

#### Table 11. Static characteristics

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  to 55  $\Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Pin V <sub>CC</sub>						
I <sub>CC</sub>	supply current	Standby mode with no undervoltage; $T_{vj} \leq 85~^{\circ}C$	-	20	30	μA
		Standby mode with no undervoltage; $T_{\nu j} \leq 150~^\circ\text{C}$	-	20	40	μA
		Power-off mode; $T_{vj} \leq 85~^{\circ}C$	-	-	30	μΑ
		Power-off mode; $T_{vj} \leq 150~^\circ C$	-	-	40	μA
		Normal mode; V <sub>BGE</sub> = 0 V or V <sub>TXEN</sub> = V <sub>IO</sub>	-	11	22	mA
		Normal mode; V <sub>BGE</sub> = V <sub>IO</sub> ; V <sub>TXEN</sub> = 0 V	-	40	60	mA
		Normal mode; $V_{BGE} = V_{IO}$ ; $V_{TXEN} = 0$ ; V; $R_{bus} > 10 M\Omega$	-	25	40	mA
V <sub>uvd(VCC)</sub>	undervoltage detection voltage on pin $V_{CC}$		4.45	-	4.729	V
V <sub>uvr(VCC)</sub>	undervoltage recovery voltage on pin $V_{CC}$		4.47	-	4.749	V
V <sub>uvhys(VCC)</sub>	undervoltage hysteresis voltage on pin $V_{CC}$		20	-	290	mV
V <sub>th(det)</sub> POR	power-on reset detection threshold voltage		3.75	-	4.15	V
V <sub>th(rec)</sub> POR	power-on reset recovery threshold voltage		3.85	-	4.25	V
V <sub>hys(POR)</sub>	power-on reset hysteresis voltage		100	-	500	mV
Pin V <sub>IO</sub>						
I <sub>IO</sub>	supply current on pin V <sub>IO</sub>	Normal mode; $V_{TXEN} = V_{IO}$ ; $V_{BGE} = V_{IO}$ ; $R_{RXD} > 10 M\Omega$	-	-	1000	μA
		Normal mode; $V_{TXEN} = 0 V$ ; $V_{BGE} = V_{IO}$ ; $R_{RXD} > 10 M\Omega$	-	-	1000	μA
		Standby mode with no undervoltage	-	2.2	7	μA
		Power-off mode; $V_{IO} = 5 V$	-	3	7	μA
V <sub>uvd(VIO)</sub>	undervoltage detection voltage on pin V <sub>IO</sub>		2.55	-	2.774	V
V <sub>uvr(VIO)</sub>	undervoltage recovery voltage on pin V <sub>IO</sub>		2.575	-	2.799	V
V <sub>uvhys(VIO)</sub>	undervoltage hysteresis voltage on pin V <sub>IO</sub>		25	-	240	mV
Pin SCSN						
V <sub>IH</sub>	HIGH-level input voltage		0.7V <sub>IO</sub>	-	5.5	V
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#### Table 11. Static characteristics ...continued

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  to 55  $\Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>IL</sub>	LOW-level input voltage		-0.3	-	0.3V <sub>IO</sub>	V
I <sub>IH</sub>	HIGH-level input current	Simple error indication mode; $V_{SCSN} = 0.7 V_{IO}$	3	-	15	μA
IIL	LOW-level input current	SPI mode; $V_{SCSN} = 0.3 V_{IO}$	-15	-	-3	μA
l <sub>r</sub>	reverse current	Power-off mode; to $V_{CC}/V_{IO}$ ; $V_{SCSN} = 5 V$ ; $V_{CC} = V_{IO} = 0 V$	-5	0	+5	μA
Pin SCLK						
V <sub>IH</sub>	HIGH-level input voltage		0.7V <sub>IO</sub>	-	5.5	V
V <sub>IL</sub>	LOW-level input voltage		-0.3	-	$0.3V_{\text{IO}}$	V
I <sub>IH</sub>	HIGH-level input current	$V_{SCLK} = V_{IO}$	-1	0	+1	μA
IIL	LOW-level input current	$V_{SCLK} = 0.3 V_{IO}$	-15	-	-3	μA
l <sub>r</sub>	reverse current	Power-off mode; to $V_{CC}/V_{IO}$ ; $V_{SCLK} = 5 V$ ; $V_{CC} = V_{IO} = 0 V$	-5	0	+5	μA
Pin STBN						
V <sub>IH</sub>	HIGH-level input voltage		0.7V <sub>IO</sub>	-	5.5	V
V <sub>IL</sub>	LOW-level input voltage		-0.3	-	$0.3V_{IO}$	V
I <sub>IH</sub>	HIGH-level input current	$V_{STBN} = 0.7 V_{IO}$	3	-	15	μA
IIL	LOW-level input current	V <sub>STBN</sub> = 0 V	-1	0	+1	μA
l <sub>r</sub>	reverse current	Power-off mode; to $V_{CC}/V_{IO}$ ; $V_{STBN} = 5 V$ ; $V_{CC} = V_{IO} = 0 V$	-5	0	+5	μA
Pin TXEN						
V <sub>IH</sub>	HIGH-level input voltage		0.7V <sub>IO</sub>	-	5.5	V
V <sub>IL</sub>	LOW-level input voltage		-0.3	-	0.3V <sub>IO</sub>	V
I <sub>IH</sub>	HIGH-level input current	$V_{TXEN} = V_{IO}$	-1	0	+1	μA
IIL	LOW-level input current	$V_{TXEN} = 0.3 V_{IO}$	-300	-	-50	μA
l <sub>r</sub>	reverse current	Power-off mode; to $V_{CC}/V_{IO}$ ; $V_{TXEN} = 5 V$ ; $V_{CC} = V_{IO} = 0 V$	-5	0	+5	μA
Pin BGE						
V <sub>IH</sub>	HIGH-level input voltage		0.7V <sub>IO</sub>	-	5.5	V
V <sub>IL</sub>	LOW-level input voltage		-0.3	-	0.3V <sub>IO</sub>	V
I <sub>IH</sub>	HIGH-level input current	$V_{BGE} = 0.6 V_{IO}$	3	-	15	μA
IIL	LOW-level input current	V <sub>BGE</sub> = 0 V	-1	0	+1	μA
l <sub>r</sub>	reverse current	Power-off mode; to $V_{CC}/V_{IO}$ ; $V_{BGE} = 5 V$ ; $V_{CC} = V_{IO} = 0 V$	-5	0	+5	μA
Pin TXD						
V <sub>IH</sub>	HIGH-level input voltage	Normal mode	0.6V <sub>IO</sub>	-	5.5	V
V <sub>IL</sub>	LOW-level input voltage	Normal mode	-0.3	-	$0.4V_{IO}$	V
I <sub>IH</sub>	HIGH-level input current	$V_{TXD} = 0.6 V_{IO}$	3	-	15	μA
I <sub>IL</sub>	LOW-level input current	$V_{TYD} = 0 V$	-1	0	+1	μA

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#### Table 11. Static characteristics ...continued

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  to 55  $\Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
l <sub>r</sub>	reverse current	Power-off mode; to $V_{CC}/V_{IO}$ ; $V_{TXD} = 5 V$ ; $V_{CC} = V_{IO} = 0 V$	-5	0	+5	μA
Ci	input capacitance	with respect to all other pins at ground; $V_{TXD} = 100 \text{ mV}$ ; f = 5 MHz	<u>[1]</u> -	-	10	pF
Pin RXD						
V <sub>OH</sub>	HIGH-level output voltage	$I_{OH(RXD)} = -1.5 \text{ mA}$	V <sub>IO</sub> –	0.4 -	V <sub>IO</sub>	V
V <sub>OL</sub>	LOW-level output voltage	$I_{OL(RXD)} = 1.5 \text{ mA}$		-	0.4	V
I <sub>OH</sub>	HIGH-level output current	$V_{RXD} = V_{IO} - 0.4 \text{ V}; V_{IO} = V_{CC}$	-15	-	-1.5	mA
I <sub>OL</sub>	LOW-level output current	$V_{RXD} = 0.4 V$	1.5	-	15	mA
Vo	output voltage	when undervoltage on V <sub>IO</sub> ; $R_L = 100 \text{ k}\Omega$ to GND	-	-	500	mV
		Power-off mode; $R_L = 100 \text{ k}\Omega \text{ to } V_{IO}$	V <sub>IO</sub> –	500 -	V <sub>IO</sub>	mV
Pin ERRN						
V <sub>OH</sub>	HIGH-level output voltage	I <sub>OH(ERRN)</sub> = -100 μA	V <sub>IO</sub> –	0.4 -	V <sub>IO</sub>	V
V <sub>OL</sub>	LOW-level output voltage	I <sub>OL(ERRN)</sub> = 200 μA	-	-	0.4	V
I <sub>OH</sub>	HIGH-level output current	$V_{ERRN} = V_{IO} - 0.4 \text{ V}; V_{IO} = V_{CC}$	-150	0 -	-100	μA
I <sub>OL</sub>	LOW-level output current	V <sub>ERRN</sub> = 0.4 V	200	-	1700	μΑ
IL	leakage current	Power-off mode; $V_{ERRN} \leq V_{IO}$	-5	-	+5	μΑ
Vo	output voltage	when undervoltage on V <sub>IO</sub> ; $R_L = 100 \text{ k}\Omega \text{ to GND}$	-	-	500	mV
		Power-off mode; $R_L = 100 \text{ k}\Omega \text{ to GND}$	-	-	500	mV
Pin SDO						
V <sub>OH</sub>	HIGH-level output voltage	$I_{OH(SDO)} = -0.5 \text{ mA}$	V <sub>IO</sub> –	0.4 -	V <sub>IO</sub>	V
V <sub>OL</sub>	LOW-level output voltage	$I_{OL(SDO)} = 0.8 \text{ mA}$	-	-	0.4	V
I <sub>OH</sub>	HIGH-level output current	$V_{SDO} = V_{IO} - 0.4 V$	-8	-3	-0.5	mA
I <sub>OL</sub>	LOW-level output current	$V_{SDO} = 0.4 V$	0.8	3	9	mA
IL	leakage current	high-impedance state; 0 V < V <sub>SDO</sub> < V <sub>IO</sub>	-5	-	+5	μA

### Table 11. Static characteristics ...continued

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  to 55  $\Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Vo	output voltage	when undervoltage on V <sub>IO</sub> ; V <sub>CC</sub> > 4.75 V; R <sub>L</sub> = 100 k $\Omega$ to GND		-500	-	+500	mV
		Power-off mode; $R_L = 100 \text{ k}\Omega \text{ to GND}$		-	-	500	mV
Pins BP and	BM						
V <sub>o(idle)(BP)</sub>	idle output voltage on	Normal mode; $V_{TXEN} = V_{IO}$		$0.4V_{CC}$	$0.5V_{CC}$	$0.6V_{CC}$	V
	pin BP	Standby mode with no undervoltage on pin $V_{CC}$		-0.1	0	+0.1	V
V <sub>o(idle)(BM)</sub>	idle output voltage on	Normal mode; $V_{TXEN} = V_{IO}$		$0.4V_{CC}$	$0.5V_{CC}$	$0.6V_{CC}$	V
	pin BM	Standby mode with no undervoltage on pin $V_{CC}$		-0.1	0	+0.1	V
o(idle)BP	idle output current on pin BP	Normal and Standby modes with no undervoltage; –60 V $\leq$ V_{BP} $\leq$ +60 V		-7.5	-	+7.5	mA
I <sub>o(idle)</sub> BM	idle output current on pin BM	Normal and Standby modes with no undervoltage; –60 V $\leq$ V_{BM} $\leq$ +60 V		-7.5	-	+7.5	mA
V <sub>o(idle)(dif)</sub>	differential idle output voltage	Normal mode		-25	0	+25	mV
V <sub>OH(dif)</sub>	differential HIGH-level	$4.75~\text{V} \leq \text{V}_{CC} \leq 5.25~\text{V}$		900	-	2000	mV
	output voltage	$4.45~\text{V} \leq \text{V}_{CC} \leq 5.25~\text{V}$		700	-	2000	mV
V <sub>OL(dif)</sub>	differential LOW-level	$4.75~\text{V} \leq \text{V}_{CC} \leq 5.25~\text{V}$		-2000	-	-900	mV
	output voltage	$4.45~\text{V} \leq \text{V}_{CC} \leq 5.25~\text{V}$		-2000		-700	mV
V <sub>IH(dif)</sub>	differential HIGH-level input voltage	Normal mode; –10 V $\leq V_{cm} \leq$ +15 V	[2]	150	225	300	mV
V <sub>IL(dif)</sub>	differential LOW-level	Normal mode; –10 V $\leq$ V $_{cm}$ $\leq$ +15 V	[2]	-300	-225	-150	mV
	input voltage	Standby mode with no undervoltage on pin V <sub>CC</sub> ; -10 V $\leq$ V <sub>cm</sub> $\leq$ +15 V	[2]	-400	-225	-100	mV
$ \Delta V_{i(dif)(H-L)} $	differential input volt. diff. betw. HIGH- and LOW-levels (abs. value)	$V_{cm} = 2.5 V$	[2]	-	-	30	mV
V <sub>i(dif)det(act)</sub>	activity detection differential input voltage (absolute value)			150	225	300	mV
I <sub>O(sc)</sub>	short-circuit output current (absolute value)	on pin BP; –5 V $\leq$ V_{BP} $\leq$ +60 V; $R_{sc} \leq$ 1 $\Omega;  t_{sc} \geq$ 1500 $\mu s$	<u>[4][6]</u>	-	-	72	mA
		on pin BP; -5 V $\leq$ V <sub>BP</sub> $\leq$ +27 V; $R_{sc} \leq$ 1 $\Omega;  t_{sc} \geq$ 1500 $\mu s$	<u>[4][6]</u>	-	-	60	mA
		on pin BM; -5 V $\leq$ V <sub>BM</sub> $\leq$ +60 V; $R_{sc} \leq$ 1 $\Omega;$ $t_{sc} \geq$ 1500 $\mu s$	<u>[4][6]</u>	-	-	72	mA
		on pin BM; -5 V $\leq$ V <sub>BM</sub> $\leq$ +27 V; $R_{sc} \leq$ 1 $\Omega;$ $t_{sc} \geq$ 1500 $\mu s$	<u>[4][6]</u>	-	-	60	mA
		on pins BP and BM; $V_{BP}$ = $V_{BM};$ $R_{sc}$ $\leq$ 1 $\Omega;$ $t_{sc}$ $\geq$ 1500 $\mu s$	<u>[5][6]</u>	-	-	60	mA
R <sub>i(BP)</sub>	input resistance on pin BP	$R_{bus} = \infty \Omega$		10	20	40	kΩ
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#### Table 11. Static characteristics ... continued

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  to 55  $\Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
R <sub>i(BM)</sub>	input resistance on pin BM	$R_{bus} = \infty \Omega$		10	20	40	kΩ
R <sub>i(dif)(BP-BM)</sub>	differential input resistance between pin BP and pin BM	$R_{bus} = \infty \Omega$		20	40	80	kΩ
I <sub>LI(BP)</sub>	input leakage current on pin BP	Power-off mode; $V_{CC}$ = $V_{IO}$ = 0 V; 0 V $\leq$ $V_{BP}$ $\leq$ 5 V		-5	0	+5	μA
		loss of ground; $V_{BP} = V_{BM} = 0$ V; all other pins connected to 16 V via 0 $\Omega$	[1]	-1600	-	+1600	μA
I <sub>LI(BM)</sub>	input leakage current on pin BM	Power-off mode; V_{CC} = V_{IO} = 0 V; 0 V $\leq$ V_{BM} $\leq$ 5 V		-5	0	+5	μA
		loss of ground; $V_{BP} = V_{BM} = 0$ V; all other pins connected to 16 V via 0 $\Omega$	[1]	-1600	-	+1600	μA
V <sub>cm(bus)</sub> (DATA_0)	DATA_0 bus common-mode voltage	Normal mode		$0.4V_{CC}$	$0.5V_{CC}$	0.65V <sub>CC</sub>	V
V <sub>cm(bus)</sub> (DATA_1)	DATA_1 bus common-mode voltage	Normal mode		$0.4V_{CC}$	$0.5V_{CC}$	$0.65V_{CC}$	V
$\Delta V_{\text{cm(bus)}}$	bus common-mode voltage difference	Normal mode; DATA_1 – DATA_0		-25	0	+25	mV
C <sub>i(BP)</sub>	input capacitance on pin BP	with respect to all other pins at ground; $V_{BP}$ = 100 mV; f = 5 MHz	<u>[1]</u>	-	-	15	pF
C <sub>i(BM)</sub>	input capacitance on pin BM	with respect to all other pins at ground; $V_{BM}$ = 100 mV; f = 5 MHz	<u>[1]</u>	-	-	15	pF
C <sub>i(dif)(BP-BM)</sub>	differential input capacitance between pin BP and pin BM	with respect to all other pins at ground; $V_{BP} = 100 \text{ mV}$ ; $V_{BM} = 100 \text{ mV}$ ; f = 5 MHz	<u>[1]</u>	-	-	5	pF
Z <sub>o(eq)TX</sub>	transmitter equivalent output impedance	Normal mode; $C_{bus}$ = 100 pF; $R_{bus}$ = 40 $\Omega$ or 100 $\Omega$	<u>[3]</u>	10	-	600	Ω
Temperature p	rotection						
T <sub>j(dis)(high)</sub>	high disable junction temperature			180	-	200	°C

[1] Guaranteed by design.

[2]  $V_{cm}$  is the BP/BM common mode voltage.

[3]  $Z_{o(TX)(eq)} = 50 \ \Omega \times (V_{bus(100)} - V_{bus(40)})/(2.5 \times V_{bus(40)} - V_{bus(100)})$ , where:  $V_{bus(100)} =$  the differential output voltage on a load of 100  $\Omega$  and 100 pF in parallel.  $V_{bus(40)} =$  the differential output voltage on a load of 40  $\Omega$  and100 pF in parallel, when driving a DATA\_1.

[4] R<sub>sc</sub> is the short-circuit resistance; voltage difference between bus pins BP and BM is 60 V max.

[5]  $R_{sc}$  is the short-circuit resistance between BP and BM.

[6] t<sub>sc</sub> is the minimum duration of the short-circuit

# **10.** Dynamic characteristics

#### Table 12. Dynamic characteristics

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Pins BP and B	Μ						
t <sub>d(TXD-bus)</sub>	delay time from TXD to bus	Normal mode	[1][2]				
		DATA_0		-	-	60	ns
		DATA_1		-	-	60	ns
$\Delta t_{d(TXD-bus)}$	delay time difference from TXD to bus	Normal mode; between DATA_0 and DATA_1; Normal mode	<u>[1][2]</u>	-4	-	+4	ns
t <sub>d(bus-RXD)</sub>	delay time from bus to RXD	Normal mode; $C_{RXD} = 25 \text{ pF}$ ; $V_{cm} = 2.5 \text{ V}$	<u>[3][4]</u>				
		DATA_0		-	-	75	ns
		DATA_1		-	-	75	ns
$\Delta t_{\sf d(bus-RXD)}$	delay time difference from bus to RXD	between DATA_0 and DATA_1; Normal mode; $C_{RXD} = 25 \text{ pF}; V_{cm} = 2.5 \text{ V}$	<u>[3][4]</u>	-5	-	5	ns
t <sub>d(TXEN-busidle)</sub>	delay time from TXEN to bus idle	Normal mode; V <sub>TXD</sub> = 0 V	[5]	-	-	75	ns
t <sub>d(TXEN-busact)</sub>	delay time from TXEN to bus active	Normal mode; V <sub>TXD</sub> = 0 V	[5]	-	-	75	ns
$ \Delta t_{d(TXEN-bus)} $	delay time difference from TXEN to bus (absolute value)	Normal mode; between TXEN to bus active and TXEN to bus idle; $V_{TXD} = 0 V$	<u>[6][5]</u>			50	ns
t <sub>d(BGE-busidle)</sub>	delay time from BGE to bus idle	Normal mode; V <sub>TXD</sub> = 0 V	[5]	-	-	75	ns
t <sub>d(BGE-busact)</sub>	delay time from BGE to bus active	Normal mode; V <sub>TXD</sub> = 0 V	[5]	-	-	75	ns
t <sub>r(dif)(bus)</sub>	bus differential rise time	DATA_0 to DATA_1; 20 % to 80 %	<u>[5]</u>	6	-	18.75	ns
t <sub>f(dif)(bus)</sub>	bus differential fall time	DATA_1 to DATA_0; 80 % to 20 %	[5]	6	-	18.75	ns
$\Delta t_{(r-f)(dif)}$	difference between differential rise and fall time	on bus; 80 % to 20 %	<u>[5]</u>	-3	-	3	ns
t <sub>f(bus)</sub> (idle-act)	bus fall time from idle to active	bus idle to DATA_0; –30 mV > V <sub>dif</sub> > –300 mV	<u>[5][7]</u>	-	-	30	ns
t <sub>f(bus)(act-idle)</sub>	bus fall time from active to idle	DATA_1 to bus idle; 300 mV > V <sub>dif</sub> > 30 mV	<u>[5][7]</u>	-	-	30	ns
t <sub>r(bus)(act-idle)</sub>	bus rise time from active to idle	DATA_0 to bus idle; –300 mV < V <sub>dif</sub> < –30 mV	<u>[5][7]</u>	-	-	30	ns
Wake-up detec	tion						
t <sub>det(wake)</sub> DATA_0	DATA_0 wake-up detection time	Standby mode with no undervoltage on pin V <sub>CC</sub> ; $-10 \text{ V} \leq V_{cm} \leq +15 \text{ V}$	<u>[3][8]</u>	1	-	4	μS
t <sub>det(wake)</sub> idle	idle wake-up detection time	Standby mode with no undervoltage on pin V <sub>CC</sub> ; $-10 \text{ V} \le \text{V}_{cm} \le +15 \text{ V}$	<u>[3][8]</u>	1	-	4	μS

#### Table 12. Dynamic characteristics ...continued

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
t <sub>det(wake)tot</sub>	total wake-up detection time	Standby mode with no undervoltage on pin V <sub>CC</sub> ; $-10 V \le V_{cm} \le +15 V$	<u>[3][8]</u>	50	-	115	μS
t <sub>sup(int)wake</sub>	wake-up interruption suppression time	Standby mode with no undervoltage on pin V <sub>CC</sub> ; $-10 \text{ V} \le \text{V}_{cm} \le +15 \text{ V}$	<u>[3][9]</u>	130	-	1000	ns
t <sub>d(wake-ERRN)</sub>	delay time from wake-up to ERRN	Standby mode		-	-	100	μS
$t_{d(wake-RXD)}$	delay time from wake-up to RXD	Standby mode		-	-	100	μs
Undervoltage							
t <sub>det(uv)(VCC)</sub>	undervoltage detection time on pin $V_{\mbox{CC}}$	0 V $\leq$ V $_{IO}$ $\leq$ 5.5 V; V $_{CC}$ = 4.35 V		2	-	100	μS
t <sub>rec(uv)(VCC)</sub>	undervoltage recovery time on pin $V_{CC}$	0 V $\leq$ V $_{IO}$ $\leq$ 5.5 V; V $_{CC}$ = 4.85 V		2	-	100	μS
t <sub>det(uv)(VIO)</sub>	undervoltage detection time on pin $V_{\text{IO}}$	$V_{th(det)POR} < V_{CC} < 5.5 V;$ $V_{IO} = 2.45 V$		5	-	100	μS
t <sub>rec(uv)(VIO)</sub>	undervoltage recovery time on pin $V_{\text{IO}}$	$V_{th(det)POR} < V_{CC} < 5.5 V;$ $V_{IO} = 2.9 V$		5	-	100	μS
Activity detection	on						
t <sub>det(act)(bus)</sub>	activity detection time on bus pins	Normal mode; $V_{cm} = 2.5 V$ ; $V_{dif}$ : 0 mV $\rightarrow$ 400 mV	<u>[3][7]</u>	100	-	250	ns
$t_{det(idle)(bus)}$	idle detection time on bus pins	Normal mode; $V_{cm} = 2.5 V$ ; $V_{dif}$ : 400 mV $\rightarrow$ 0 mV	<u>[3][7]</u>	100	-	200	ns
$ \Delta t_{det(act-idle)} $	active to idle detection time difference (absolute value)	Normal mode; on bus pins; $V_{cm} = 2.5 V$	[3]	-	-	150	ns
ERRN signaling	3						
t <sub>det(L)(SCLK)</sub>	LOW-level detection time on pin SCLK	Normal or Standby mode with no undervoltage on pin V <sub>IO</sub>		95	-	310	μS
t <sub>ERRNL(min)</sub>	minimum ERRN LOW time	simple error indication mode; Normal or Standby mode		2	-	10	μS
$t_{d(errdet-ERRNL)}$	delay time from error detection to ERRN LOW	all modes		-	-	100	μS
SPI							
$t_{d(SCSNHL-SDOL)}$	SCSN falling edge to SDO LOW-level delay time	$V_{uvd(VIO)} < V_{IO} < 5.5 V;$ 4.45 V < V <sub>CC</sub> < 5.5 V; C <sub>SDO</sub> = 50 pF	<u>[10]</u>	-	-	250	ns
$t_{d(SCLKLH-SDODV)}$	SCLK rising edge to SDO data valid delay time	$V_{uvd(VIO)} < V_{IO} < 5.5 V;$ 4.45 V < V <sub>CC</sub> < 5.5 V; C <sub>SDO</sub> = 50 pF	<u>[10]</u>	-	-	200	ns
$t_{d}(SCSNLH-SDOZ)$	SCSN rising edge to SDO three-state delay time	$V_{uvd(VIO)} < V_{IO} < 5.5 V;$ 4.45 V < $V_{CC} < 5.5 V;$ $C_{SDO} = 50 \text{ pF}$	[10]	-	-	500	ns
T <sub>SCLK</sub>	SCLK period	$V_{uvd(VIO)} < V_{IO} < 5.5 V;$ 4.45 V < $V_{CC} < 5.5 V;$ $C_{SDO} = 50 \text{ pF}$	<u>[10]</u>	0.5	-	100	μS

#### Table 12. Dynamic characteristics ...continued

All parameters are guaranteed for  $V_{CC} = 4.45$  V to 5.25 V;  $V_{IO} = 2.55$  V to 5.25 V;  $T_{vj} = -40$  °C to +150 °C;  $R_{bus} = 40 \Omega$  and  $C_{bus} = 100$  pF unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
t <sub>SPILEAD</sub>	SPI enable lead time	V <sub>uvd(VIO)</sub> < V <sub>IO</sub> < 5.5 V; 4.45 V < V <sub>CC</sub> < 5.5 V; C <sub>SDO</sub> = 50 pF	<u>[10]</u>	250	-	-	ns
t <sub>SPILAG</sub>	SPI enable lag time	$V_{uvd(VIO)} < V_{IO} < 5.5 V;$ 4.45 V < $V_{CC} < 5.5 V;$ $C_{SDO} = 50 \text{ pF}$	<u>[10]</u>	250	-	-	ns
RXD							
t <sub>r</sub>	rise time	20 % to 80 %; C <sub>RXD</sub> = 15 pF	[6]	-	-	9	ns
		20 % to 80 %; $C_{RXD}$ = 25 pF	[6]	-	-	10.75	ns
t <sub>f</sub>	fall time	80 % to 20 %; $C_{RXD}$ = 15 pF	[6]	-	-	9	ns
		80 % to 20 %; $C_{RXD}$ = 25 pF	[6]	-	-	10.75	ns
$\Delta t_{(r-f)}$ di	difference between rise and fall time	C <sub>RXD</sub> = 15 pF	[6]	-	-	5	ns
		$C_{RXD} = 25 \text{ pF}$	[6]	-	-	5	ns
		C <sub>RXD</sub> = 10 pF; simulated	<u>[6][11]</u>	-	-	5	ns
t <sub>(r+f)</sub>	sum of rise and fall time	C <sub>RXD</sub> = 15 pF	[6]	-	-	13	ns
		C <sub>RXD</sub> = 25 pF	<u>[6]</u>	-	-	16.5	ns
		C <sub>RXD</sub> = 10 pF; simulated	<u>[6][11]</u>	-	-	16.5	ns
Bus error flag							
t <sub>d(norm-stb)</sub>	normal mode to standby delay time	bus error flag set		3	-	10	μs
t <sub>d(stb-norm)</sub>	standby to normal mode delay time	bus error flag set		3	-	10	μs
Miscellaneous							
t <sub>detCL(TXEN)</sub>	TXEN clamp detection time			650	-	2600	μs
t <sub>detCL(BGE)</sub>	BGE clamp detection time			650	-	2600	μs
t <sub>d(TXENH-RXDH)</sub>	delay time from TXEN HIGH to RXD HIGH	idle loop delay; Normal mode; TXD = LOW; $V_{cm} = 2.5 V$ ; $C_{RXD} = 25 pF$	<u>[3]</u>	-	-	300	ns

[1] Sum of TXD rise and fall times (20 % to 80 %);  $t_{r(TXD)} + t_{f(TXD)} = max. 9 ns.$ 

- [2] See Figure 13.
- [3]  $V_{cm}$  is the BP/BM common mode voltage.
- [4] See Figure 14.
- [5] See Figure 13.
- [6] Guaranteed by design.
- $[7] \quad V_{dif} = V_{BP} V_{BM}.$
- [8] See Figure 8.
- [9] See Figure 9.
- [10] See Figure 11.

[11] Load at end of 50  $\Omega$  microstrip with a propagation delay of 1 ns; 20 % to 80 % and 80 % to 20 %.

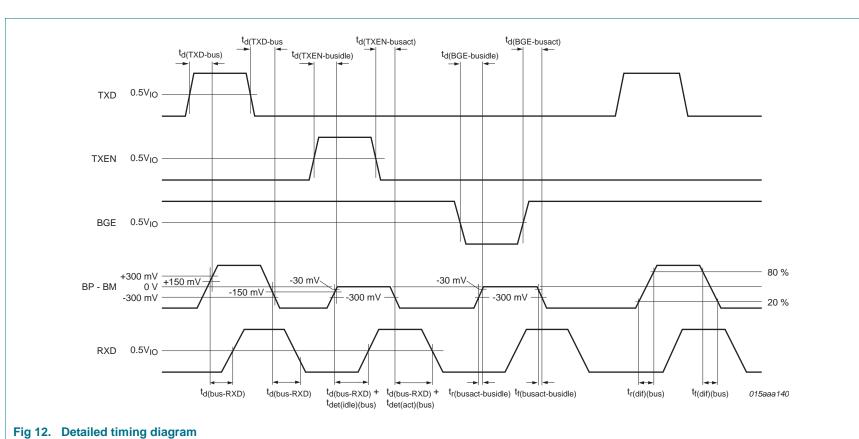
TJA1083



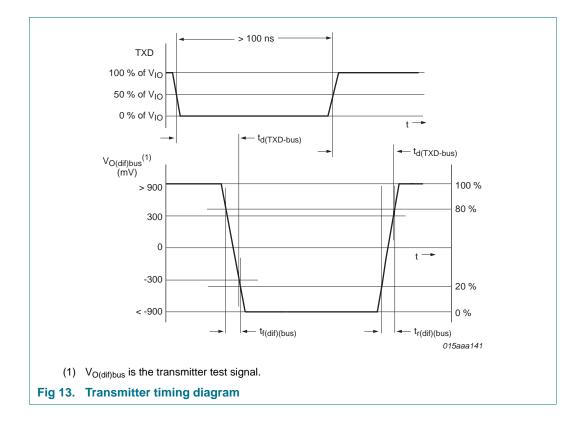




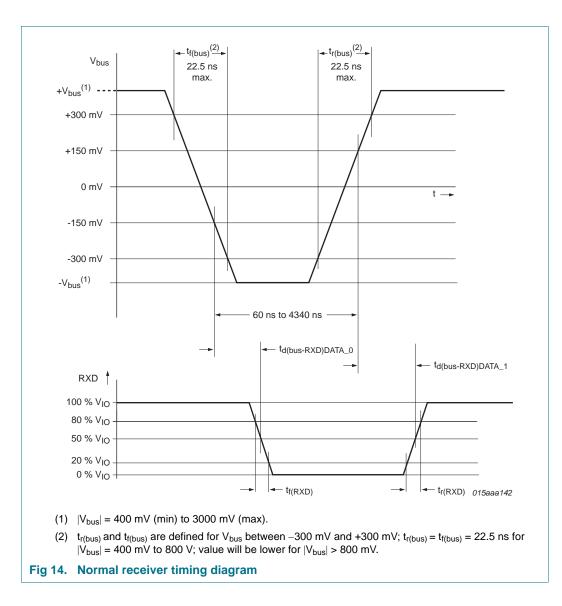
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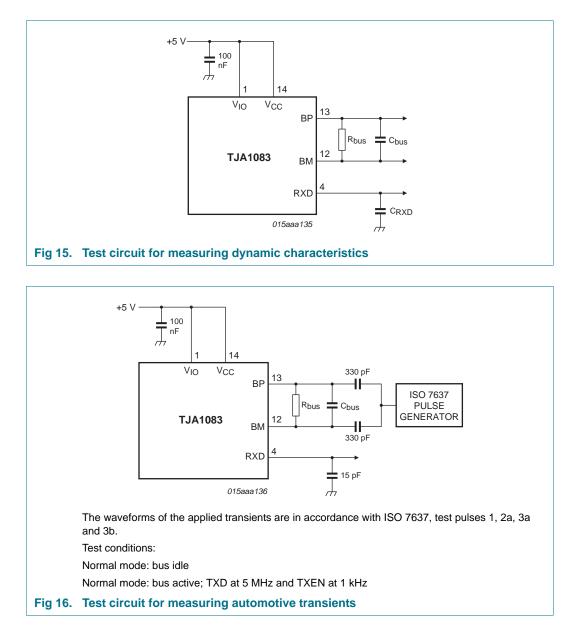


FlexRay node transceiver



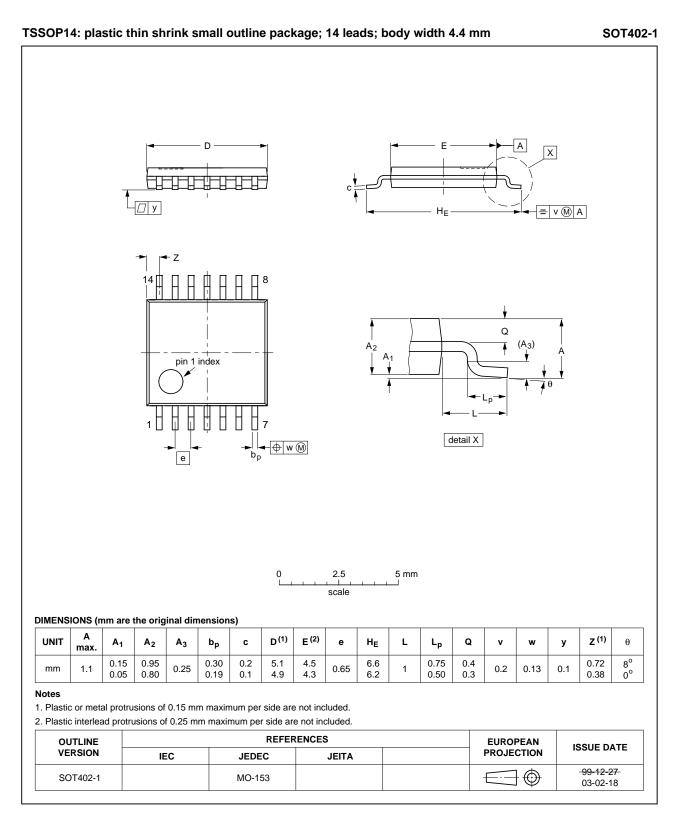
TJA1083 Product data sheet

# **11. Test information**



TJA1083 FlexRay node transceiver

# 12. Package outline



#### Fig 17. Package outline SOT402-1 (TSSOP14)

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# 13. Soldering of SMD packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note *AN10365 "Surface mount reflow soldering description"*.

# 13.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

# 13.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leaded or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leaded SMDs with leads having a pitch smaller than ~0.6 mm cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leaded packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- · Board specifications, including the board finish, solder masks and vias
- Package footprints, including solder thieves and orientation
- The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus SnPb soldering

## 13.3 Wave soldering

Key characteristics in wave soldering are:

- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- Solder bath specifications, including temperature and impurities

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## 13.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see <u>Figure 18</u>) than a SnPb process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with Table 13 and 14

#### Table 13. SnPb eutectic process (from J-STD-020C)

Package thickness (mm)	Package reflow temperature (°C)				
	Volume (mm <sup>3</sup> )				
	< 350	≥ 350			
< 2.5	235	220			
≥ 2.5	220	220			

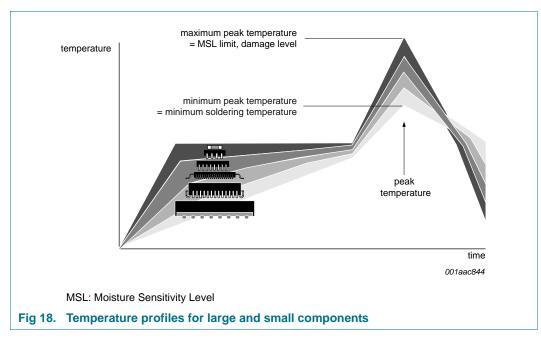
#### Table 14. Lead-free process (from J-STD-020C)

Package thickness (mm)	Package reflow temperature (°C) Volume (mm <sup>3</sup> )					
	< 350	350 to 2000	> 2000			
< 1.6	260	260	260			
1.6 to 2.5	260	250	245			
> 2.5	250	245	245			

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see Figure 18.

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For further information on temperature profiles, refer to Application Note *AN10365 "Surface mount reflow soldering description"*.

# 14. Appendix

## 14.1 Differences between TJA1082 and TJA1083

The main differences between the TJA1083 and the TJA1082 are:

- The TJA1083 is EPL V3.0.1 compliant whereas the TJA1082 is EPL V2.1 Rev. B compliant
- The TJA1083 is JASPAR compliant (minimum transmitter output voltage of 900 mV)
- The TJA1083 has a higher pulse immunity (ISO7637)
- The TJA1083 has improved EMC behavior
- The bus load conditions for the static and dynamic characteristics are different in EPL V3.0.1 compared to EPL V2.1 Rev. B: 40 Ω to 55 Ω for the static characteristics instead of 40 Ω and 40 Ω for the dynamic characteristics instead of 45 Ω.

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# 14.2 Implementation of EPL 3.0.1 requirements in the TJA1083

### Table 15. EPL 3.0.1 implementation in TJA1083

dBDRxAsym dBDRx10 dBDRx01 dBDRxai dBDRxai dBDRxia dBDTxAsym dBDTx10 dBDTx01 dBDTx01 dBDTxai dBusTxai dBusTxai dBusTxai dBusTx10 uBDTX <sub>active</sub>	Min 50 100 6 6 600	Max 5 75 275 325 4 75 75 75 75 30 30 30 18.75 18.75 2000	Unit ns ns ns ns ns ns ns ns ns ns ns ns ns	Symbol $ \Delta t_{d(bus-RXD)} $ $t_{d(bus-RXD)}$ $t_{d(bus-RXD)}$ $t_{d(bus-RXD)}$ $t_{det(idle)(bus)} + t_{d(bus-RXD)}$ $t_{det(idle)(bus)} + t_{d(bus-RXD)}$ $t_{det(act)(bus)} + t_{d(bus-RXD)}$ $t_{d(TXD-bus)}$ $t_{d(TXD-bus)}$ $t_{d(TXD-bus)}$ $t_{d(TXEN-busidle)}$ $t_{d(TXEN-busact)}$ $t_{d(TXEN-busact)}$ $t_{f(bus)(act-idle)}$ $t_{f(bus)(idle-act)}$ $t_{r(dif)(bus)}$	Min 0 - 100 100 0 - - - - - 6 6	Max         5         75         275         325         4         60         75         30         30         18.75	Unit ns ns ns ns ns ns ns ns ns ns ns ns
dBDRx10 dBDRx01 dBDRxai dBDRxia dBDTxAsym dBDTx10 dBDTx01 dBDTx01 dBDTxai dBDTxia dBusTxai dBusTxia dBusTxia dBusTx10 uBDTx <sub>active</sub>	50 100 - - - - - - - 6 6 6	75 75 275 325 4 75 75 75 75 30 30 30 18.75 18.75	ns ns ns ns ns ns ns ns ns ns ns ns ns	$\begin{array}{l} t_{d(bus-RXD)} \\ t_{d(bus-RXD)} \\ t_{d(bus-RXD)} \\ t_{det(idle)(bus)} + t_{d(bus-RXD)} \\ t_{det(act)(bus)} + t_{d(bus-RXD)} \\ [\Delta t_{d(TXD-bus)}] \\ t_{d(TXD-bus)} \\ t_{d(TXD-bus)} \\ t_{d(TXD-bus)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{f(bus)(idle-act)} \\ t_{f(dif)(bus)} \\ \end{array}$	- 100 100 0 - - - - - - - - 6	75 75 275 325 4 60 60 75 75 30 30	ns ns ns ns ns ns ns ns ns ns ns
dBDRx01 dBDRxai dBDRxia dBDTxAsym dBDTx10 dBDTx01 dBDTxai dBDTxai dBusTxai dBusTxai dBusTx10 uBDTx <sub>active</sub>	50 100 - - - - - - - 6 6 6	75 275 325 4 75 75 75 75 30 30 30 18.75 18.75	ns ns ns ns ns ns ns ns ns ns ns	$ \begin{array}{l} t_{d(bus-RXD)} \\ t_{det(idle)(bus)} + t_{d(bus-RXD)} \\ t_{det(act)(bus)} + t_{d(bus-RXD)} \\  \Delta t_{d(TXD-bus)}  \\ t_{d(TXD-bus)} \\ t_{d(TXD-bus)} \\ t_{d(TXD-bus)} \\ t_{d(TXEN-busidle)} \\ t_{d$	100 100 - - - - - - - 6	75 275 325 4 60 60 75 75 30 30	ns ns ns ns ns ns ns ns ns ns
dBDRxai dBDRxia dBDTxAsym dBDTx10 dBDTx01 dBDTxai dBDTxia dBusTxia dBusTxia dBusTxia dBusTx10 uBDTx <sub>active</sub>	50 100 - - - - - - - 6 6 6	275 325 4 75 75 75 30 30 30 18.75 18.75	ns ns ns ns ns ns ns ns ns ns ns	$\begin{array}{l} t_{det(idle)(bus)} + t_{d(bus-RXD)} \\ t_{det(act)(bus)} + t_{d(bus-RXD)} \\  \Delta t_{d(TXD-bus)}  \\ t_{d(TXD-bus)} \\ t_{d(TXD-bus)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{f(bus)(act-idle)} \\ t_{f(bus)(idle-act)} \\ t_{r(dif)(bus)} \\ \end{array}$	100 100 - - - - - - - 6	275 325 4 60 60 75 75 30 30	ns ns ns ns ns ns ns ns ns
dBDRxia dBDTxAsym dBDTx10 dBDTx01 dBDTxai dBDTxia dBusTxai dBusTxai dBusTx10 uBDTx <sub>active</sub>	100 - - - - - - - 6 6 6 00	325 4 75 75 75 75 30 30 30 18.75 18.75	ns ns ns ns ns ns ns ns ns	$\begin{array}{l} t_{det(act)(bus)} + t_{d(bus-RXD)} \\  \Delta t_{d(TXD-bus)}  \\ t_{d(TXD-bus)} \\ t_{d(TXD-bus)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busidle)} \\ t_{d(TXEN-busact)} \\ t_{f(bus)(act-idle)} \\ t_{f(bus)(idle-act)} \\ t_{r(dif)(bus)} \\ \end{array}$	100 0 - - - - - - 6	325 4 60 60 75 75 30 30	ns ns ns ns ns ns ns ns
dBDTxAsym dBDTx10 dBDTx01 dBDTxai dBDTxia dBusTxai dBusTxia dBusTxi0 dBusTx10 uBDTx <sub>active</sub>	- - - - - - 6 6 6 600	4 75 75 75 30 30 18.75 18.75	ns ns ns ns ns ns ns ns ns	$\begin{split} & \Delta t_{d(TXD-bus)}  \\ &t_{d(TXD-bus)} \\ &t_{d(TXD-bus)} \\ &t_{d(TXEN-busidle)} \\ &t_{d(TXEN-busact)} \\ &t_{d(TXEN-busact)} \\ &t_{r(bus)(act-idle)} \\ &t_{f(bus)(idle-act)} \\ &t_{r(dif)(bus)} \\ \end{split}$	0 - - - - - 6	4 60 75 75 30 30	ns ns ns ns ns ns
dBDTx10 dBDTx01 dBDTxai dBDTxia dBusTxai dBusTxia dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	75 75 75 30 30 18.75 18.75	ns ns ns ns ns ns ns ns	td(TXD-bus)         td(TXD-bus)         td(TXEN-busidle)         td(TXEN-busact)         td(TXEN-busact)         tr(bus)(act-idle)         tf(bus)(idle-act)         tr(dif)(bus)	- - - - - 6	60 60 75 75 30 30	ns ns ns ns ns
dBDTx01 dBDTxai dBDTxia dBusTxai dBusTxia dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	75 75 30 30 18.75 18.75	ns ns ns ns ns ns	td(TXD-bus) td(TXEN-busidle) td(TXEN-busact) tr(bus)(act-idle) tf(bus)(idle-act) tr(dif)(bus)	- - - - 6	60 75 75 30 30	ns ns ns ns ns
dBDTxai dBDTxia dBusTxai dBusTxia dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	75 75 30 30 18.75 18.75	ns ns ns ns ns	t <sub>d</sub> (TXEN-busidle) t <sub>d</sub> (TXEN-busact) t <sub>r</sub> (bus)(act-idle) t <sub>f</sub> (bus)(idle-act) t <sub>r</sub> (dif)(bus)	- - 6	75 75 30 30	ns ns ns ns
dBDTxia dBusTxai dBusTxia dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	75 30 30 18.75 18.75	ns ns ns ns ns	t <sub>d(TXEN-busact)</sub> t <sub>r(bus)(act-idle)</sub> t <sub>f(bus)(idle-act)</sub> t <sub>r(dif)(bus)</sub>	- - 6	75 30 30	ns ns ns
dBusTxai dBusTxia dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	30 30 18.75 18.75	ns ns ns ns	t <sub>r(bus)(act-idle)</sub> t <sub>f(bus)(idle-act)</sub> t <sub>r(dif)(bus)</sub>	- 6	30 30	ns ns
dBusTxia dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	30 18.75 18.75	ns ns ns	t <sub>f(bus)</sub> (idle-act) t <sub>r(dif)(bus)</sub>	- 6	30	ns
dBusTx01 dBusTx10 uBDTx <sub>active</sub>	6 600	18.75 18.75	ns ns	t <sub>r(dif)(bus)</sub>			
dBusTx10 uBDTx <sub>active</sub>	6 600	18.75	ns			18.75	nc
uBDTx <sub>active</sub>	600			t <sub>f(dif)(bus)</sub>	6		ns
		2000	. <i>.</i>		ю	18.75	ns
	0		mV	V <sub>OH(dif)</sub>	900	2000	mV
uBDTx <sub>idle</sub>	0	30	mV	V <sub>o(idle)(dif)</sub>	0	25	mV
uV <sub>DIG-OUT-HIGH</sub>	80	100	%	V <sub>OH(RXD)</sub>	$V_{IO}-0.4$	V <sub>IO</sub>	V
				V <sub>OH(ERRN)</sub>	$V_{IO}-0.4$	V <sub>IO</sub>	V
uV <sub>DIG-OUT-LOW</sub>	-	20	%	V <sub>OL(RXD)</sub>	-	0.4	V
				V <sub>OL(ERRN)</sub>	-	0.4	V
uV <sub>DIG-IN-HIGH</sub>	-	70	%	V <sub>IH(TXEN)</sub>	0.7V <sub>IO</sub>	5.5	V
				V <sub>IH(STBN)</sub>	0.7V <sub>IO</sub>	5.5	V
				V <sub>IH(BGE)</sub>	0.7V <sub>IO</sub>	5.5	V
uV <sub>DIG-IN-LOW</sub>	30	-	%	V <sub>IL(TXEN)</sub>	-0.3	+0.3V <sub>IO</sub>	V
				V <sub>IL(STBN)</sub>	-0.3	+0.3V <sub>IO</sub>	V
				V <sub>IL(BGE)</sub>	-0.3	+0.3V <sub>IO</sub>	V
uData0	-300	-150	mV	V <sub>IL(dif)</sub>	-300	-150	mV
uData1	150	300	mV	V <sub>IH(dif)</sub>	150	300	mV
uData1- uData0	-30	30	mV	∆V <sub>i(dif)(H-L)</sub>	-	30	mV
dBDActivityDetection	100	250	ns	t <sub>det(act)(bus)</sub>	100	250	ns
dBDIdleDetection	50	200	ns	t <sub>det(idle)(bus)</sub>	100	200	ns
R <sub>CM1</sub> , R <sub>CM2</sub>	10	40	kΩ	R <sub>i(BP)</sub> , R <sub>i(BM)</sub>	10	40	kΩ
uCM	-10	15	V	V <sub>cm</sub> [1]	-10	+15	V
iBM <sub>GNDShortMax</sub>	-	60	mA	I <sub>O(sc)(BM)</sub>	-	60	mA
iBP <sub>GNDShortMax</sub>	-	60	mA	I <sub>O(sc)(BP)</sub>	-	60	mA
iBM <sub>BAT48ShortMax</sub>	-	72	mA	I <sub>O(sc)(BM)</sub>	-	72	mA
iBP <sub>BAT48ShortMax</sub>	-	72	mA	I <sub>O(sc)(BP)</sub>	-	72	mA
iBM <sub>BAT27ShortMax</sub>	-	60	mA	I <sub>O(sc)(BM)</sub>	-	60	mA

TJA1083 Product data sheet

FlexRay node transceiver

## Table 15. EPL 3.0.1 implementation in TJA1083

EPL 3.0.1				TJA1083				
	Min	Мах	Unit	Symbol	Min	Max	Uni	
iBP <sub>BAT27ShortMax</sub>	-	60	mA	I <sub>O(sc)(BP)</sub>	-	60	mA	
uBias, non low-power modes	1800	3200	mV	V <sub>o(idle)(BP)</sub> , V <sub>o(idle)(BM)</sub> [2]	1800	3150	mV	
uBias, low-power modes	-200	200	mV	V <sub>o(idle)(BP)</sub> , V <sub>o(idle)(BM)</sub> [3]	-0.1	+0.1	V	
dWU <sub>0Detect</sub>	1	4	μS	t <sub>det(wake)DATA_0</sub>	1	4	μS	
dWU <sub>IdleDetect</sub>	1	4	μS	t <sub>det(wake)idle</sub>	1	4	μS	
dWU <sub>Timeout</sub>	48	140	μS	t <sub>det(wake)tot</sub>	50	115	μS	
uBDUVV <sub>CC</sub>	4	-	V	V <sub>uvd(VCC)</sub>	4.45	4.729	V	
dBDUVV <sub>CC</sub>	-	1000	ms	t <sub>det(uv)(VCC)</sub>	2	100	μS	
BP <sub>Leak</sub>	-	25	μΑ	I <sub>LI(BP)</sub>	-5	+5	μA	
BM <sub>Leak</sub>	-	25	μΑ	I <sub>LI(BM)</sub>	-5	+5	μA	
Functional class 'bus driver logic evel adaptation'				implemented; see Section 2.4				
Functional class 'bus driver - bus guardian interface'				implemented; see Section 2.4				
Device qualification according to AEC-Q100 (Rev. F)				see <u>Section 2.1</u>				
T <sub>AMB_Class1</sub>	-40	125	°C	T <sub>amb</sub>	-40	+125	°C	
BDTxDM	-50	50	ns	$\Delta t_{d(TXEN-bus)}$	-50	50	ns	
BM <sub>-5VshortMax</sub>	-	60	mA	I <sub>O(sc)(BM)</sub>	-	60	mA	
BP-5VshortMax	-	60	mA	I <sub>O(sc)(BP)</sub>	-	60	mA	
BM <sub>BPShortMax</sub>	-	60	mA	I <sub>O(sc)(BM)</sub>	-	60	mA	
BP <sub>BMShortMax</sub>	-	60	mA	I <sub>O(sc)(BP)</sub>	-	60	mA	
BM <sub>BAT60ShortMax</sub>	-	90	mA	I <sub>O(sc)(BM)</sub>	-	72	mA	
BP <sub>BAT60ShortMax</sub>	-	90	mA	I <sub>O(sc)(BP)</sub>	-	72	mA	
uUV <sub>IO</sub>	2	-	V	V <sub>uvd(VIO)</sub>	2.55	2.774	V	
dBDUVV <sub>IO</sub>	-	1000	ms	t <sub>det(uv)(VIO)</sub>	5	100	μS	
dBDWakeupReaction <sub>remote</sub>	-	100	μS	$t_{d(wake\text{-}ERRN)},t_{d(wake\text{-}RXD)}$	-	100	μS	
dBDTxActiveMax	650	2600	μS	$t_{detCL(TXEN)}$	650	2600	μS	
dBDModeChange	100	100	μS	t <sub>d(norm-stb)</sub> , t <sub>d(stb-norm)</sub>	3	10	μS	
dBDERRN <sub>Stable</sub>	1	10	μS	t <sub>ERRN(min)</sub>	2	10	μS	
dReactionTime <sub>ERRN</sub>	-	100	μS	t <sub>d(errdet</sub> -ERRNL)	-	100	μS	
uData0_LP	-400	-100	mV	V <sub>IL(dif)</sub>	-400	-100	mV	
dWU <sub>Interrupt</sub>	0.13	1	μS	t <sub>sup(int)wake</sub>	130	1000	ns	
uBDLogic_1	-	60	%	V <sub>IH(TXD)</sub>	$0.6V_{IO}$	5.5	V	
uBDLogic_0	40	-	%	V <sub>IL(TXD)</sub>	-0.3	$0.4 V_{IO}$	V	
dBDRV <sub>CC</sub>	-	10	ms	t <sub>rec(uv)(VCC)</sub>	2	100	μS	
dBDRV <sub>IO</sub>	-	10	ms	t <sub>rec(uv)(VIO)</sub>	5	100	μS	
iBP <sub>LeakGND</sub>	-	1600	μΑ	I <sub>LI(BP)</sub>	-1600	1600	μA	
iBM <sub>LeakGND</sub>	-	1600	μΑ	I <sub>LI(BM)</sub>	-1600	1600	μA	
Functional class 'bus driver remote wakeup'				implemented; see Section 2.4				

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Product data sheet

TJA1083

FlexRay node transceiver

#### Table 15. EPL 3.0.1 implementation in TJA1083

EPL 3.0.1			TJA1083				
	Min	Max	Unit	Symbol	Min	Max	Unit
Functional class 'bus driver increased voltage amplitude transmitter'				implemented; see <u>Section 2.4</u>			
uESD <sub>Ext</sub>	6	-	kV	$ V_{\text{ESD}} $ : HBM on pins BP and BM to GND	-	8	kV
uESD <sub>Int</sub>	2	-	kV	$ V_{ESD} $ : HBM on any other pin	-	4	kV
uESD <sub>IEC</sub>	6	-	kV	V <sub>ESD</sub>   : IEC61000-4-2 on pins BP and BM to GND	-	8	kV
$dBDRxD_{R15} + dBDRxD_{F15}$	-	13	ns	$\Sigma t_{(r+f)}$ (pin RXD; 15 pF load)	-	13	ns
$ dBDRxD_{R15}-dBDRxD_{F15} \\$	-	5	ns	$ \Delta t_{(r\text{-}f)} $ (pin RXD; 15 pF load)	-	5	ns
C_BDTxD	-	10	pF	C <sub>i(TXD)</sub>	-	10	pF
dBDTxRxai	-	325	ns	t <sub>d(TXENH-RXDH)</sub>	-	300	ns
uV <sub>DIG-OUT-UV</sub>	- 50	500	mV	V <sub>O(UVVIO)RXD</sub>	-	500	mV
				V <sub>O(UVVIO)ERRN</sub>	-	500	mV
				V <sub>O(UVVIO)SDO</sub>	-	500	mV
uV <sub>DIG-OUT-OFF</sub>	product specific			V <sub>OL(RXD)</sub> [4]	$V_{IO}-500$	V <sub>IO</sub>	mV
				V <sub>OL(ERRN)</sub> [4]	-	500	mV
				V <sub>OL(SDO)</sub> [4]	-	500	mV
R <sub>BDTransmitter</sub>	product	specific		Z <sub>o(TX)(eq)</sub>	10	600	Ω
RxD signal sum of rise and fall time at TP4_CC	-	16.5	ns	$\sum t_{(r+f)}$ (pin RXD; 10 pF load; simulated)	-	16.5	ns
dBDRxD <sub>R25</sub> + dBDRxD <sub>F25</sub>	-	16.5	ns	$\sum t_{(r+f)}$ (pin RXD; 25 pF load)	-	16.5	ns
dBDRxD <sub>R25</sub> – dBDRxD <sub>F25</sub>	-	5	ns	$ \Delta t_{(r-f)} $ (pin RXD; 25 pF load)	-	5	ns
dBusTxDif	-	3	ns	$ \Delta t_{(r-f)(dif)} $	-	3	ns
RxD signal difference of rise and fall time at TP4_CC	-	5	ns	$ \Delta t_{(r-f)} $ (pin RXD; 10 pF load; simulated)	-	5	ns

[1] V<sub>cm</sub> is the BP/BM common mode voltage, (V<sub>BP</sub> + V<sub>BM</sub>) / 2, and is specified in conditions column of parameters V<sub>IH(dif)</sub> and V<sub>IL(dif)</sub> for pins BP and BM; see <u>Table 11</u>. V<sub>cm</sub> is tested on a receiving bus driver with a transmitting bus driver that has a ground offset voltage in the range -12.5 V to +12.5 V and transmits a 50/50 pattern.

[3] The normal voltage is 0 mV.

[4] Power-off mode.

# **15. Abbreviations**

Table 16. Abbreviations				
Abbreviation	Description			
CDM	Charged Device Model			
ECU	Electronic Control Unit			
EMC	ElectroMagnetic Compatibility			
EME	ElectroMagnetic Emission			
EMI	ElectroMagnetic Immunity			
ESD	ElectroStatic Discharge			
HBM	Human Body Model			
JASPAR	Japan Automotive Software Platform Architecture			
MM	Machine Model			
PWON	Power-on			

# 16. References

- [1] EPL FlexRay Communications System Electrical Physical Layer Specification Version 3.0.1 (expected to be released by the end of 2009)
- [2] AN Application hint AN10365 Surface mount reflow soldering description

# 17. Revision history

Table 17. Revision hist	ory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
TJA1083 v.1	20121010	Product data sheet	-	-

# **18. Legal information**

## 18.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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